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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

E·XFI

Product Status	Active
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	113
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx32a-1tqg144

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Ordering Information



Notes:

1. For more information about the CQFP package options, refer to the HiRel SX-A datasheet.

2. All –3 speed grades have been discontinued.

Device Resources

	User I/Os (Including Clock Buffers)							
Device	208-Pin PQFP	100-Pin TQFP	144-Pin TQFP	176-Pin TQFP	329-Pin PBGA	144-Pin FBGA	256-Pin FBGA	484-Pin FBGA
A54SX08A	130	81	113	-	-	111	-	-
A54SX16A	175	81	113	-	-	111	180	-
A54SX32A	174	81	113	147	249	111	203	249
A54SX72A	171	-	-	-	-	_	203	360

Notes: Package Definitions: PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array, FBGA = Fine Pitch Ball Grid Array



Temperature Grade Offering

Package	A54SX08A	A54SX16A	A54SX32A	A54SX72A
PQ208	C,I,A,M	C,I,A,M	C,I,A,M	C,I,A,M
TQ100	C,I,A,M	C,I,A,M	C,I,A,M	
TQ144	C,I,A,M	C,I,A,M	C,I,A,M	
TQ176			C,I,M	
BG329			C,I,M	
FG144	C,I,A,M	C,I,A,M	C,I,A,M	
FG256		C,I,A,M	C,I,A,M	C,I,A,M
FG484			C,I,M	C,I,A,M
CQ208			C,M,B	C,M,B
CQ256			C,M,B	C,M,B

Notes:

1. C = Commercial

- 2. I = Industrial
- 3. A = Automotive
- 4. M = Military
- 5. B = MIL-STD-883 Class B

6. For more information regarding automotive products, refer to the SX-A Automotive Family FPGAs datasheet.

7. For more information regarding Mil-Temp and ceramic packages, refer to the HiRel SX-A Family FPGAs datasheet.

Speed Grade and Temperature Grade Matrix

	F	Std	-1	-2	-3
Commercial	1	1	1	1	Discontinued
Industrial		1	1	1	Discontinued
Automotive		1			
Military		1	1		
MIL-STD-883B		1	1		

Notes:

1. For more information regarding automotive products, refer to the SX-A Automotive Family FPGAs datasheet.

2. For more information regarding Mil-Temp and ceramic packages, refer to the HiRel SX-A Family FPGAs datasheet.

Contact your Actel Sales representative for more information on availability.



Figure 1-5 • DirectConnect and FastConnect for Type 1 SuperClusters



Figure 1-6 • DirectConnect and FastConnect for Type 2 SuperClusters

Power-Up/Down and Hot Swapping

SX-A I/Os are configured to be hot-swappable, with the exception of 3.3 V PCI. During power-up/down (or partial up/down), all I/Os are tristated. V_{CCA} and V_{CCI} do not have to be stable during power-up/down, and can be powered up/down in any order. When the SX-A device is plugged into an electrically active system, the device will not degrade the reliability of or cause damage to the host system. The device's output pins are driven to a high impedance state until normal chip operating conditions

are reached. Table 1-4 summarizes the V_{CCA} voltage at which the I/Os behave according to the user's design for an SX-A device at room temperature for various ramp-up rates. The data reported assumes a linear ramp-up profile to 2.5 V. For more information on power-up and hot-swapping, refer to the application note, Actel SX-A and RT54SX-S Devices in Hot-Swap and Cold-Sparing Applications.

Function	Description			
Input Buffer Threshold Selections	 5 V: PCI, TTL 3.3 V: PCI, LVTTL 2.5 V: LVCMOS2 (commercial only) 			
Flexible Output Driver	 5 V: PCI, TTL 3.3 V: PCI, LVTTL 2.5 V: LVCMOS2 (commercial only) 			
Output Buffer	 "Hot-Swap" Capability (3.3 V PCI is not hot swappable) I/O on an unpowered device does not sink current Can be used for "cold-sparing" Selectable on an individual I/O basis Individually selectable slew rate; high slew or low slew (The default is high slew rate). The slew is only affected on the falling edge of an output. Rising edges of outputs are not affected. 			
Power-Up	Individually selectable pull-ups and pull-downs during power-up (default is to power-up in tristate) Enables deterministic power-up of device V _{CCA} and V _{CCI} can be powered in any order			

Table 1-2 • I/O Features

Table 1-3 • I/O Characteristics for All I/O Configurations

	Hot Swappable	Slew Rate Control	Power-Up Resistor
TTL, LVTTL, LVCMOS2	Yes	Yes. Only affects falling edges of outputs	Pull-up or pull-down
3.3 V PCI	No	No. High slew rate only	Pull-up or pull-down
5 V PCI	Yes	No. High slew rate only	Pull-up or pull-down

Table 1-4 • Power-Up Time at which I/Os Become Active

Supply Ramp Rate	0.25 V/ μs	0.025 V/ μs	5 V/ms	2.5 V/ms	0.5 V/ms	0.25 V/ms	0.1 V/ms	0.025 V/ms
Units	μs	μs	ms	ms	ms	ms	ms	ms
A54SX08A	10	96	0.34	0.65	2.7	5.4	12.9	50.8
A54SX16A	10	100	0.36	0.62	2.5	4.7	11.0	41.6
A54SX32A	10	100	0.46	0.74	2.8	5.2	12.1	47.2
A54SX72A	10	100	0.41	0.67	2.6	5.0	12.1	47.2

Electrical Specifications

Table 2-5 • 3.3 V LVTTL and 5 V TTL Electrical Specifications

			Comm	ercial	Indus	strial	
Symbol	Parameter		Min.	Max.	Min.	Max.	Units
V _{OH}	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	$(I_{OH} = -1 \text{ mA})$	0.9 V _{CCI}		0.9 V _{CCI}		V
	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	(I _{OH} = -8 mA)	2.4		2.4		V
V _{OL}	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	(I _{OL} = 1 mA)		0.4		0.4	V
	$V_{CCI} = Minimum$ $V_I = V_{IH} \text{ or } V_{IL}$	(I _{OL} = 12 mA)		0.4		0.4	V
V _{IL}	Input Low Voltage			0.8		0.8	V
V _{IH}	Input High Voltage		2.0	5.75	2.0	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μA
I _{OZ}	Tristate Output Leakage Current		-10	10	-10	10	μΑ
t _R , t _F	Input Transition Time t _R , t _F			10		10	ns
C _{IO}	I/O Capacitance			10		10	pF
I _{CC}	Standby Current			10		20	mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at http://www.actel.com/download/ibis/default.aspx.

Table 2-6 • 2.5 V LVCMOS2 Electrical Specifications

			Comn	nercial	Indu	strial	
Symbol	Parameter		Min.	Max.	Min.	Max.	Units
V _{OH}	$V_{DD} = MIN,$	$(I_{OH} = -100 \ \mu A)$	2.1		2.1		V
	$V_{I} = V_{IH} \text{ or } V_{IL}$						
	$V_{DD} = MIN,$ $V_{I} = V_{UI} \text{ or } V_{U}$	$(I_{OH} = -1 \text{ mA})$	2.0		2.0		V
		(l - 2mA)	17		17		V
	$V_{DD} = V_{IH}$ or V_{IL}	(I _{OH} =2 IIIA)	1.7		1.7		v
V _{OL}	$V_{DD} = MIN,$	(I _{OL} = 100 μA)		0.2		0.2	V
	$V_{I} = V_{IH} \text{ or } V_{IL}$						
	$V_{DD} = MIN,$	(I _{OL} = 1 mA)		0.4		0.4	V
	$V_{I} = V_{IH} \text{ or } V_{IL}$	-					
	$V_{DD} = MIN,$	(I _{OL} = 2 mA)		0.7		0.7	V
	$V_{I} = V_{IH} \text{ or } V_{IL}$						
V _{IL}	Input Low Voltage, $V_{OUT} \le V_{VOL(max)}$		-0.3	0.7	-0.3	0.7	V
V _{IH}	Input High Voltage, $V_{OUT} \ge V_{VOH(min)}$		1.7	5.75	1.7	5.75	V
$I_{\rm IL}/I_{\rm IH}$	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μΑ
I _{OZ}	Tristate Output Leakage Current, $V_{OUT} = V_{CCI}$ or GND		-10	10	-10	10	μA
t _R , t _F	Input Transition Time t _R , t _F			10		10	ns
C _{IO}	I/O Capacitance			10		10	pF
I _{CC}	Standby Current			10		20	mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at http://www.actel.com/download/ibis/default.aspx.

Symbol	Parameter	Condition	Min.	Max.	Units
I _{OH(AC)}	Switching Current High	$0 < V_{OUT} \le 0.3 V_{CCI}^{1}$	–12V _{CCI}	-	mA
		$0.3V_{CCI} \le V_{OUT} < 0.9V_{CCI}$ ¹	(-17.1(V _{CCI} - V _{OUT}))	_	mA
		0.7V _{CCI} < V _{OUT} < V _{CCI} ^{1, 2}	_	EQ 2-3 on page 2-7	-
	(Test Point)	$V_{OUT} = 0.7 V_{CC}^2$	-	-32V _{CCI}	mA
I _{OL(AC)}	Switching Current Low	$V_{CCI} > V_{OUT} \ge 0.6 V_{CCI}^{1}$	16V _{CCI}	-	mA
		$0.6V_{CCI} > V_{OUT} > 0.1V_{CCI}^{1}$	(26.7V _{OUT})	-	mA
		0.18V _{CCI} > V _{OUT} > 0 ^{1, 2}	_	EQ 2-4 on page 2-7	-
	(Test Point)	$V_{OUT} = 0.18 V_{CC}^2$	-	38V _{CCI}	mA
I _{CL}	Low Clamp Current	$-3 < V_{IN} \le -1$	–25 + (V _{IN} + 1)/0.015	-	mA
I _{CH}	High Clamp Current	$V_{CCI} + 4 > V_{IN} \ge V_{CCI} + 1$	25 + (V _{IN} – V _{CCI} – 1)/0.015	-	mA
slew _R	Output Rise Slew Rate	0.2V _{CCI} - 0.6V _{CCI} load ³	1	4	V/ns
slew _F	Output Fall Slew Rate	$0.6V_{CCI} - 0.2V_{CCI} \log^3$	1	4	V/ns

Table 2-10 • AC Specifications (3.3 V PCI Operation)

Notes:

1. Refer to the V/I curves in Figure 2-2 on page 2-7. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.

- 2. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 2-2 on page 2-7. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
- 3. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.





Where:

- C_{EQCM} = Equivalent capacitance of combinatorial modules (C-cells) in pF
- C_{EQSM} = Equivalent capacitance of sequential modules (R-Cells) in pF
- C_{EQI} = Equivalent capacitance of input buffers in pF
- C_{EQO} = Equivalent capacitance of output buffers in pF
- C_{EQCR} = Equivalent capacitance of CLKA/B in pF
- C_{EQHV} = Variable capacitance of HCLK in pF
- C_{EQHF} = Fixed capacitance of HCLK in pF
 - C_{L =} Output lead capacitance in pF
 - f_m = Average logic module switching rate in MHz
 - $f_n =$ Average input buffer switching rate in MHz
 - f_p = Average output buffer switching rate in MHz
 - $f_{a1} =$ Average CLKA rate in MHz
 - $f_{\alpha 2}$ = Average CLKB rate in MHz
 - f_{s1} = Average HCLK rate in MHz
 - m = Number of logic modules switching at fm
 - n = Number of input buffers switching at fn
 - p = Number of output buffers switching at fp
 - q₁ = Number of clock loads on CLKA
 - q₂ = Number of clock loads on CLKB
 - $r_1 =$ Fixed capacitance due to CLKA
 - r₂ = Fixed capacitance due to CLKB
 - s1 = Number of clock loads on HCLK
 - x = Number of I/Os at logic low
 - y = Number of I/Os at logic high

Table 2-11 • CEQ Values for SX-A Devices

	A54SX08A	A54SX16A	A54SX32A	A54SX72A
Combinatorial modules (C _{EQCM})	1.70 pF	2.00 pF	2.00 pF	1.80 pF
Sequential modules (C _{EQCM})	1.50 pF	1.50 pF	1.30 pF	1.50 pF
Input buffers (C _{EQI})	1.30 pF	1.30 pF	1.30 pF	1.30 pF
Output buffers (C _{EQO})	7.40 pF	7.40 pF	7.40 pF	7.40 pF
Routed array clocks (C _{EQCR})	1.05 pF	1.05 pF	1.05 pF	1.05 pF
Dedicated array clocks – variable (C _{EQHV})	0.85 pF	0.85 pF	0.85 pF	0.85 pF
Dedicated array clocks – fixed (C_{EQHF})	30.00 pF	55.00 pF	110.00 pF	240.00 pF
Routed array clock A (r ₁)	35.00 pF	50.00 pF	90.00 pF	310.00 pF

Theta-JA

Junction-to-ambient thermal resistance (θ_{JA}) is determined under standard conditions specified by JESD-51 series but has little relevance in actual performance of the product in real application. It should be employed with caution but is useful for comparing the thermal performance of one package to another.

A sample calculation to estimate the absolute maximum power dissipation allowed (worst case) for a 329-pin PBGA package at still air is as follows. i.e.:

$$\theta_{JA} = 17.1^{\circ}$$
C/W is taken from Table 2-12 on page 2-11

 $T_A = 125$ °C is the maximum limit of ambient (from the datasheet)

Max. Allowed Power =
$$\frac{\text{Max Junction Temp - Max. Ambient Temp}}{\theta_{JA}} = \frac{150^{\circ}\text{C} - 125^{\circ}\text{C}}{17.1^{\circ}\text{C/W}} = 1.46 \text{ W}$$

EQ 2-11

The device's power consumption must be lower than the calculated maximum power dissipation by the package.

The power consumption of a device can be calculated using the Actel power calculator. If the power consumption is higher than the device's maximum allowable power dissipation, then a heat sink can be attached on top of the case or the airflow inside the system must be increased.

Theta-JC

Junction-to-case thermal resistance (θ_{JC}) measures the ability of a device to dissipate heat from the surface of the chip to the top or bottom surface of the package. It is applicable for packages used with external heat sinks and only applies to situations where all or nearly all of the heat is dissipated through the surface in consideration. If the power consumption is higher than the calculated maximum power dissipation of the package, then a heat sink is required.

Calculation for Heat Sink

For example, in a design implemented in a FG484 package, the power consumption value using the power calculator is 3.00 W. The user-dependent data T_J and T_A are given as follows:

$$T_{J} = 110^{\circ}C$$

 $T_{A} = 70^{\circ}C$

From the datasheet:

 $\theta_{JA} = 18.0^{\circ}C/W$ $\theta_{JC} = 3.2^{\circ}C/W$

$$P = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{110^{\circ}\text{C} - 70^{\circ}\text{C}}{18.0^{\circ}\text{C/W}} = 2.22 \text{ W}$$

EQ 2-12

The 2.22 W power is less than then required 3.00 W; therefore, the design requires a heat sink or the airflow where the device is mounted should be increased. The design's junction-to-air thermal resistance requirement can be estimated by:

$$\theta_{JA} = \frac{Max Junction Temp - Max. Ambient Temp}{P} = \frac{110^{\circ}C - 70^{\circ}C}{3.00 W} = 13.33^{\circ}C/W$$

EQ 2-13

Table 2-15 • A54SX08A Timing Characteristics

(Worst-Case Commercial Condition	s V _{CCA} = 2.25 V, V _C	_{CI} = 2.25 V, T _J = 70°C)
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		-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (Hardwired) Array Clock Networks				8				8		
t _{НСКН}	Input Low to High (Pad to R-cell Input)		1.4		1.6		1.8		2.6	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.3		1.5		1.7		2.4	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.4		0.5		0.7	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Arra	y Clock Networks									
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.0		1.1		1.3		1.8	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.2		1.4		2.0	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.0		1.1		1.3		1.8	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2.0	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2.0	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.4	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.7	ns

Table 2-16 A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions	V _{CCA} = 2.25 V, V _{CC}	₁ = 3.0 V, T _J = 70°C)
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		-2 S	peed	-1 S	peed	Std.	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (H	lardwired) Array Clock Networks									
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.3		1.5		1.7		2.6	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.1		1.3		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPVVL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.5		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Arra	y Clock Networks									
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.2		1.4		1.9	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.2		1.3		1.6		2.2	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPVVL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.8		0.9		1.1		1.5	ns

Table 2-21 A54SX16A Timing Characteristics (Continued)

(Morst Case Commercial	Conditions V	- 2 25 V V	-20VT - 70°C
(worst-case commercian	Contractions, v_{cl}	$c_{\Lambda} = \mathbf{Z} \cdot \mathbf{Z} \mathbf{J} \mathbf{V} \mathbf{V} c_{\Gamma}$	$= 3.0 v, 1_1 = 70 C$
•			

		-3 Sp	beed ¹	-2 S	peed	-1 Speed Std. Speed		Speed	I –F Speed			
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.5		0.6		0.7		0.9	ns
t _{INYL}	Input Data Pad to Y Low 5 V PCI		0.7		0.8		0.9		1.1		1.5	ns
t _{INYH}	Input Data Pad to Y High 5 V TTL		0.5		0.5		0.6		0.7		0.9	ns
t _{INYL}	Input Data Pad to Y Low 5 V TTL		0.7		0.8		0.9		1.1		1.5	ns
Input Modu	le Predicted Routing Delays ²											
t _{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.3		0.4		0.6	ns
t _{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.5		0.6		0.8	ns
t _{IRD3}	FO = 3 Routing Delay		0.5		0.6		0.7		0.8		1.1	ns
t _{IRD4}	FO = 4 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t _{IRD8}	FO = 8 Routing Delay		1.2		1.4		1.5		0.8		2.5	ns
t _{IRD12}	FO = 12 Routing Delay		1.7		2.0		2.2		2.6		3.6	ns

Notes:

1. All –3 speed grades have been discontinued.

2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-27 A54SX16A Timing Characteristics

		-3 Speed ¹	-2 S	peed	–1 Sp	eed	Std. 9	Speed	–F S	peed	
Parameter	Description	Min. Max	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
5 V PCI Out	put Module Timing ²										
t _{DLH}	Data-to-Pad Low to High	2.2		2.5		2.8		3.3		4.6	ns
t _{DHL}	Data-to-Pad High to Low	2.8		3.2		3.6		4.2		5.9	ns
t _{ENZL}	Enable-to-Pad, Z to L	1.3		1.5		1.7		2.0		2.8	ns
t _{ENZH}	Enable-to-Pad, Z to H	2.2		2.5		2.8		3.3		4.6	ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.0		3.5		3.9		4.6		6.4	ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.8		3.2		3.6		4.2		5.9	ns
d _{TLH} ³	Delta Low to High	0.016		0.016		0.02		0.022		0.032	ns/pF
d _{THL} ³	Delta High to Low	0.026		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Out	put Module Timing ⁴								-		
t _{DLH}	Data-to-Pad Low to High	2.2		2.5		2.8		3.3		4.6	ns
t _{DHL}	Data-to-Pad High to Low	2.8		3.2		3.6		4.2		5.9	ns
t _{DHLS}	Data-to-Pad High to Low—low slew	6.7		7.7		8.7		10.2		14.3	ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.7		3.2		4.5	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4		8.4		9.5		11.0		15.4	ns
t _{ENZH}	Enable-to-Pad, Z to H	1.9		2.2		2.5		2.9		4.1	ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.6		4.2		4.7		5.6		7.8	ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.5		2.9		3.3		3.9		5.4	ns
d _{TLH} ³	Delta Low to High	0.014		0.017		0.017		0.023		0.031	ns/pF
d _{THL} ³	Delta High to Low	0.023		0.029		0.031		0.037		0.051	ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.043		0.046		0.057		0.066		0.089	ns/pF

Notes:

1. All –3 speed grades have been discontinued.

2. Delays based on 50 pF loading.

3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate [V/ns] = (0.1* V_{CCI} – 0.9* V_{CCI} / (C_{load} * $d_{T[LH|HL|HLS]}$) where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

4. Delays based on 35 pF loading.

Table 2-36 • A54SX72A Timing Characteristics (Continued)

(Worst-Case Commercial Conditions $V_{CCA} = 2.25 V$, $V_{CCI} = 2.25 V$, $T_J = 70^{\circ}C$:)
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		-3 Sp	beed*	-2 S	peed	–1 Speed Std.		Std. 9	Std. Speed -F Sp		peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t _{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.9		3.4		3.8		4.5		6.3	ns
t _{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t _{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t _{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All –3 speed grades have been discontinued.

Table 2-38 A54SX72A Timing Characteristics

(Worst-Case Commercial Conditions V _{CCA}	= 2.25 V, V _{CCl} = 4.75 V, T _J = 70°C
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		-3 Sr	beed*	-2 S	peed	-1 S	peed	Std. Speed		ed -F Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (Hardwired) Array Clock Netwo	rks										
t _{нскн}	Input Low to High (Pad to R-cell Input)		1.6		1.8		2.1		2.4		3.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.6		1.9		2.1		2.5		3.8	ns
t _{HPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{HPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{HCKSW}	Maximum Skew		1.4		1.6		1.8		2.1		3.3	ns
t _{HP}	Minimum Period	3.0		3.4		4.0		4.6		6.4		ns
f _{HMAX}	Maximum Frequency		333		294		250		217		156	MHz
Routed Arra	ay Clock Networks											
t _{rckh}	Input Low to High (Light Load) (Pad to R-cell Input)		2.3		2.6		3.0		3.5		4.9	ns
t _{rckl}	Input High to Low (Light Load) (Pad to R-cell Input)		2.8		3.2		3.6		4.3		6.0	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.5		2.9		3.2		3.8		5.3	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		3.0		3.4		3.9		4.6		6.4	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.6		3.0		3.4		3.9		5.5	ns
t _{rckl}	Input High to Low (100% Load) (Pad to R-cell Input)		3.2		3.6		4.1		4.8		6.8	ns
t _{RPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t _{RPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.9		2.2		2.5		3.0		4.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		1.9		2.2		2.5		3.0		4.1	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.9		2.2		2.5		3.0		4.1	ns
Quadrant A	rray Clock Networks											-
t _{QCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.6	ns
t _{QCHKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.3		1.4		1.6		1.9		2.7	ns
t _{QCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.4		1.6		1.8		2.1		3.0	ns
t _{QCHKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.4		1.7		1.9		2.2		3.1	ns

Note: *All –3 speed grades have been discontinued.

	256-Pii	n FBGA		256-Pin FBGA						
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function	Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function			
K5	I/O	I/O	I/O	M10	I/O	I/O	I/O			
К6	V _{CCI}	V _{CCI}	V _{CCI}	M11	I/O	I/O	I/O			
K7	GND	GND	GND	M12	NC	I/O	I/O			
K8	GND	GND	GND	M13	I/O	I/O	I/O			
К9	GND	GND	GND	M14	NC	I/O	I/O			
K10	GND	GND	GND	M15	I/O	I/O	I/O			
K11	V _{CCI}	V _{CCI}	V _{CCI}	M16	I/O	I/O	I/O			
K12	I/O	I/O	I/O	N1	I/O	I/O	I/O			
K13	I/O	I/O	I/O	N2	I/O	I/O	I/O			
K14	I/O	I/O	I/O	N3	I/O	I/O	I/O			
K15	NC	I/O	I/O	N4	I/O	I/O	I/O			
K16	I/O	I/O	I/O	N5	I/O	I/O	I/O			
L1	I/O	I/O	I/O	N6	I/O	I/O	I/O			
L2	I/O	I/O	I/O	N7	I/O	I/O	I/O			
L3	I/O	I/O	I/O	N8	I/O	I/O	I/O			
L4	I/O	I/O	I/O	N9	I/O	I/O	I/O			
L5	I/O	I/O	I/O	N10	I/O	I/O	I/O			
L6	I/O	I/O	I/O	N11	I/O	I/O	I/O			
L7	V _{CCI}	V _{CCI}	V _{CCI}	N12	I/O	I/O	I/O			
L8	V _{CCI}	V _{CCI}	V _{CCI}	N13	I/O	I/O	I/O			
L9	V _{CCI}	V _{CCI}	V _{CCI}	N14	I/O	I/O	I/O			
L10	V _{CCI}	V _{CCI}	V _{CCI}	N15	I/O	I/O	I/O			
L11	I/O	I/O	I/O	N16	I/O	I/O	I/O			
L12	I/O	I/O	I/O	P1	I/O	I/O	I/O			
L13	I/O	I/O	I/O	P2	GND	GND	GND			
L14	I/O	I/O	I/O	P3	I/O	I/O	I/O			
L15	I/O	I/O	I/O	P4	I/O	I/O	I/O			
L16	NC	I/O	I/O	P5	NC	I/O	I/O			
M1	I/O	I/O	I/O	P6	I/O	I/O	I/O			
M2	I/O	I/O	I/O	P7	I/O	I/O	I/O			
M3	I/O	I/O	I/O	P8	I/O	I/O	I/O			
M4	I/O	I/O	I/O	P9	I/O	I/O	I/O			
M5	I/O	I/O	I/O	P10	NC	I/O	I/O			
M6	I/O	I/O	I/O	P11	I/O	I/O	I/O			
M7	I/O	I/O	QCLKA	P12	I/O	I/O	I/O			
M8	PRB, I/O	PRB, I/O	PRB, I/O	P13	V _{CCA}	V _{CCA}	V _{CCA}			
M9	I/O	I/O	1/0	P14	I/O	I/O	I/O			

	A	484-Pin FBG	
P Nur	A54SX72A Function	A54SX32A Function	Pin Number
AA	NC	NC*	A1
A	NC	NC*	A2
A	I/O	NC*	A3
A	I/O	NC*	A4
A	I/O	NC*	A5
A	I/O	I/O	A6
A	I/O	I/O	A7
A	I/O	I/O	A8
A	I/O	I/O	A9
A	I/O	I/O	A10
AE	I/O	NC*	A11
AE	I/O	NC*	A12
AE	I/O	I/O	A13
AE	NC	NC*	A14
AE	I/O	NC*	A15
AE	I/O	NC*	A16
AE	I/O	I/O	A17
AE	I/O	I/O	A18
AE	I/O	I/O	A19
AB	I/O	I/O	A20
AE	I/O	NC*	A21
A	I/O	NC*	A22
AE	I/O	NC*	A23
AE	I/O	NC*	A24
AE	NC	NC*	A25
AE	NC	NC*	A26
AE	I/O	NC*	AA1
A	I/O	NC*	AA2
A	V _{CCA}	V _{CCA}	AA3
А	I/O	I/O	AA4
A	I/O	I/O	AA5
A	I/O	I/O	AA22
A	I/O	I/O	AA23
A	I/O	I/O	AA24
A	I/O	NC*	AA25

484-Pin FBGA				
Pin Number	A54SX32A Function	A54SX72A Function		
AA26	NC*	I/O		
AB1	NC*	NC		
AB2	V _{CCI}	V _{CCI}		
AB3	I/O	I/O		
AB4	I/O	ΙΟ		
AB5	NC*	ΙΟ		
AB6	I/O	ΙΟ		
AB7	I/O	ΙΟ		
AB8	I/O	I/O		
AB9	I/O	I/O		
AB10	I/O	I/O		
AB11	I/O	I/O		
AB12	PRB, I/O	PRB, I/O		
AB13	V _{CCA}	V _{CCA}		
AB14	I/O	I/O		
AB15	I/O	I/O		
AB16	I/O	I/O		
AB17	I/O	I/O		
AB18	I/O	I/O		
AB19	I/O	I/O		
AB20	TDO, I/O	TDO, I/O		
AB21	GND	GND		
AB22	NC*	I/O		
AB23	I/O	I/O		
AB24	I/O	I/O		
AB25	NC*	I/O		
AB26	NC*	I/O		
AC1	I/O	I/O		
AC2	I/O	I/O		
AC3	I/O	I/O		
AC4	NC*	I/O		
AC5	V _{CCI}	V _{CCI}		
AC6	I/O	I/O		
AC7	V _{CCI}	V _{CCI}		
AC8	I/O	I/O		

484-Pin FBGA					
Pin Number	A54SX32A Function	A54SX72A Function			
AC9	I/O	Ι/O			
AC10	I/O	I/O			
AC11	I/O	I/O			
AC12	I/O	QCLKA			
AC13	I/O	I/O			
AC14	I/O	I/O			
AC15	I/O	I/O			
AC16	I/O	I/O			
AC17	I/O	I/O			
AC18	I/O	I/O			
AC19	I/O	١/O			
AC20	V _{CCI}	V _{CCI}			
AC21	I/O	I/O			
AC22	I/O	I/O			
AC23	NC*	I/O			
AC24	I/O	I/O			
AC25	NC*	I/O			
AC26	NC*	I/O			
AD1	I/O	I/O			
AD2	I/O	I/O			
AD3	GND	GND			
AD4	I/O	I/O			
AD5	I/O	I/O			
AD6	I/O	I/O			
AD7	I/O	I/O			
AD8	I/O	I/O			
AD9	V _{CCI}	V _{CCI}			
AD10	I/O	I/O			
AD11	I/O	I/O			
AD12	I/O	I/O			
AD13	V _{CCI}	V _{CCI}			
AD14	I/O	I/O			
AD15	I/O	I/O			
AD16	I/O	I/O			
AD17	V _{CCI}	V _{CCI}			

Actel°

SX-A Family FPGAs

Note: *These pins must be left floating on the A54SX32A device.



Datasheet Information

List of Changes

The following table lists critical changes that were made in the current version of the document.

Previous Version	Changes in Current Version (v5.3)	Page
v5.2 (June 2006)	-3 speed grades have been discontinued.	N/A
	The "SX-A Timing Model" was updated with –2 data.	2-14
v5.1	RoHS information was added to the "Ordering Information".	ii
February 2005	The "Programming" section was updated.	1-13
v5.0	Revised Table 1 and the timing data to reflect the phase out of the -3 speed grade for the A54SX08A device.	i
	The "Thermal Characteristics" section was updated.	2-11
	The "176-Pin TQFP" was updated to add pins 81 to 90.	3-11
	The "484-Pin FBGA" was updated to add pins R4 to Y26	3-26
v4.0	The "Temperature Grade Offering" is new.	1-iii
	The "Speed Grade and Temperature Grade Matrix" is new.	1-iii
	"SX-A Family Architecture" was updated.	1-1
	"Clock Resources" was updated.	1-5
	"User Security" was updated.	1-7
	"Power-Up/Down and Hot Swapping" was updated.	1-7
	"Dedicated Mode" is new	1-9
	Table 1-5 is new.	1-9
	"JTAG Instructions" is new	1-10
	"Design Considerations" was updated.	1-12
	The "Programming" section is new.	1-13
	"Design Environment" was updated.	1-13
	"Pin Description" was updated.	1-15
	Table 2-1 was updated.	2-1
	Table 2-2 was updated.	2-1
	Table 2-3 is new.	2-1
	Table 2-4 is new.	2-1
	Table 2-5 was updated.	2-2
	Table 2-6 was updated.	2-2
	"Power Dissipation" is new.	2-8
	Table 2-11 was updated.	2-9

Previous Version	Changes in Current Version (v5.3)	Page
v4.0	Table 2-12 was updated.	2-11
(continued)	The was updated.	2-14
	The "Sample Path Calculations" were updated.	2-14
	Table 2-13 was updated.	2-17
	Table 2-13 was updated.	2-17
	All timing tables were updated.	2-18 to 2-52
v3.0	The "Actel Secure Programming Technology with FuseLock™ Prevents Reverse Engineering and Design Theft" section was updated.	1-i
	The "Ordering Information" section was updated.	1-ii
	The "Temperature Grade Offering" section was updated.	1-iii
	The Figure 1-1 • SX-A Family Interconnect Elements was updated.	1-1
	The ""Clock Resources" section" was updated	1-5
	The Table 1-1 • SX-A Clock Resources is new.	1-5
	The "User Security" section is new.	1-7
	The "I/O Modules" section was updated.	1-7
	The Table 1-2 • I/O Features was updated.	1-8
	The Table 1-3 • I/O Characteristics for All I/O Configurations is new.	1-8
	The Table 1-4 • Power-Up Time at which I/Os Become Active is new	1-8
	The Figure 1-12 • Device Selection Wizard is new.	1-9
	The "Boundary-Scan Pin Configurations and Functions" section is new.	1-9
	The Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved) is new.	1-11
	The "SX-A Probe Circuit Control Pins" section was updated.	1-12
	The "Design Considerations" section was updated.	1-12
	The Figure 1-13 • Probe Setup was updated.	1-12
	The Design Environment was updated.	1-13
	The Figure 1-13 • Design Flow is new.	1-11
	The "Absolute Maximum Ratings*" section was updated.	1-12
	The "Recommended Operating Conditions" section was updated.	1-12
	The "Electrical Specifications" section was updated.	1-12
	The "2.5V LVCMOS2 Electrical Specifications" section was updated.	1-13
	The "SX-A Timing Model" and "Sample Path Calculations" equations were updated.	1-23
	The "Pin Description" section was updated.	1-15
v2.0.1	The "Design Environment" section has been updated.	1-13
	The "I/O Modules" section, and Table 1-2 • I/O Features have been updated.	1-8
	The "SX-A Timing Model" section and the "Timing Characteristics" section have new timing numbers.	1-23